

1. SCOPE

1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".

1.2 Part number. The complete part number shall be as shown in the following example:

5962-87609	01	C	X
Drawing number	Device type (1.2.1)	Case outline (1.2.2)	Lead finish per MIL-M-38510

1.2.1 Device types. The device types shall identify the circuit function as follows:

Device type	Generic number	Circuit function
01	54AC04	Hex inverter
02	54AC11004	Hex inverter

1.2.2 Case outlines. The case outlines shall be as designated in appendix C of MIL-M-38510, and as follows:

Outline letter	Case outline
C	D-1 (14-lead, .785" x .310" x .200") dual-in-line package
D	F-2 (14-lead, .390" x .260" x .085") flat-package
R	D-8 (20-lead, 1.060" x .310" x .200") dual-in-line package
S	F-9 (20-lead .540" x .300" x .100") flat package
Z	C-2 (20-terminal, .358" x .358" x .100") square chip carrier package

1.3 Absolute maximum ratings.

Supply voltage range 1/	-0.5 V dc to +6.0 V dc
DC input voltage 1/	-0.5 V dc to $V_{CC} + 0.5$ V dc
DC output voltage 1/	-0.5 V dc to $V_{CC} + 0.5$ V dc
Clamp diode current	± 20 mA
DC output current (per pin)	± 50 mA
DC V_{CC} or GND current	± 100 mA
Storage temperature range	-65 °C to +150 °C
Maximum power dissipation (P_D)	500 mW
Lead temperature (soldering, 10 seconds)	+300 °C
Thermal resistance, junction-to-case (θ_{JC})	See MIL-M-38510, appendix C
Junction temperature (T_J) 2/	+175 °C

1/ Unless otherwise specified, all voltages are referenced to GND.

2/ Maximum junction temperature shall not be exceeded except for allowable short duration burn-in screening conditions in accordance with method 5004 of MIL-STD-883.

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1.4 Recommended operating conditions.

Supply voltage (V_{CC})	3/ - - - - -	3.0 V dc minimum to 5.5 V dc maximum
Input voltage	- - - - -	0.0 V dc to V_{CC}
Output voltage	- - - - -	0.0 V dc to V_{CC}
Case operating temperature range (T_C)	- - - - -	-55°C to +125°C
Input rise or fall times, $V_{CC} = 3.6$ V, $V_{CC} = 5.5$ V	- -	0 to 8 ns/V

2. APPLICABLE DOCUMENTS

2.1 Government specification, standard, and bulletin. Unless otherwise specified, the following specification, standard, and bulletin of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

BULLETIN

MILITARY

MIL-BUL-103 - List of Standardized Military Drawings (SMD's).

(Copies of the specification, standard, and bulletin required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.

3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.2 Logic diagram. The logic diagram shall be as specified on figure 2.

3.2.3 Truth table. The truth table shall be as specified on figure 3.

3/ Operation from 2.0 V dc to 3.0 V dc is provided for compatibility with data retention and battery backup systems. Data retention implies no input transitions and no stored data loss with the following conditions: $V_{IH} \geq 70\% V_{CC}$, $V_{IL} \leq 30\% V_{CC}$, $V_{OH} \geq 70\% V_{CC}$ at -20 μ A, $V_{OL} \leq 30\% V_{CC}$ at 20 μ A.

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions -55°C < T _C < +125°C unless otherwise specified		Group A subgroups	Limits		Unit
					Min	Max	
High level output voltage 1/	V _{OH}	V _{IN} = V _{IH} minimum or V _{IL} maximum, I _{OH} = -50 µA	V _{CC} = 3.0 V	1,2,3	2.9		V
			V _{CC} = 4.5 V		4.4		
			V _{CC} = 5.5 V		5.4		
		V _{IN} = V _{IH} minimum or V _{IL} maximum, I _{OH} = -4 mA	V _{CC} = 3.0 V		2.4		
			V _{CC} = 4.5 V		3.7		
			V _{CC} = 5.5 V		4.7		
Low level output voltage 1/	V _{OL}	V _{IN} = V _{IH} minimum or V _{IL} maximum, I _{OL} = 50 µA	V _{CC} = 3.0 V	1,2,3		0.1	V
			V _{CC} = 4.5 V			0.1	
			V _{CC} = 5.5 V			0.1	
		V _{IN} = V _{IH} minimum or V _{IL} maximum, I _{OL} = 12 mA	V _{CC} = 3.0 V			0.5	
			V _{CC} = 4.5 V			0.5	
			V _{CC} = 5.5 V			0.5	
		V _{IN} = V _{IH} minimum or V _{IL} maximum, I _{OL} = 50 mA	V _{CC} = 5.5 V			1.65	

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C < T _C < +125°C unless otherwise specified		Group A subgroups	Limits		Unit
					Min	Max	
High level input voltage <u>2/</u>	V _{IH}		V _{CC} = 3.0 V	1,2,3	2.1		V
			V _{CC} = 4.5 V		3.15		
			V _{CC} = 5.5 V		3.85		
Low level input voltage <u>2/</u>	V _{IL}		V _{CC} = 3.0 V	1,2,3		0.9	V
			V _{CC} = 4.5 V			1.35	
			V _{CC} = 5.5 V			1.65	
Input leakage current	I _{IL}	V _{IN} = 0.0 V	V _{CC} = 5.5 V	1,2,3		-1.0	μA
	I _{IH}	V _{IN} = 5.5 V				1.0	
Quiescent current	I _{CCH}	V _{IN} = V _{CC} or GND, V _{CC} = 5.5 V		1,2,3		80	μA
	I _{CCL}					80	
Input capacitance	C _{IN}	See 4.3.1c		4		10	pF
Power dissipation capacitance <u>3/</u>	C _{PD}	See 4.3.1c		4		105	pF
Functional tests		Tested at V _{CC} = 5.5 V, see 4.3.1d		7,8			
Propagation delay time, A to Y	t _{PHL} , t _{PLH}	C _L = 50 pF, R _L = 500Ω, See figure 4 <u>4/</u>	V _{CC} = 3.0 V	9	1.0	9.0	ns
				10,11	1.0	11.0	
			V _{CC} = 4.5 V	9	1.0	7.0	
				10,11	1.0	8.5	

See footnotes on next page.

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- 1/ V_{OH} and V_{OL} tests will be tested at $V_{CC} = 3.0$ V and $V_{CC} = 4.5$ V. $V_{CC} = 5.5$ V tests are guaranteed, but not tested. Limits shown apply to operation at $V_{CC} = 3.3$ V ± 0.3 V and $V_{CC} = 5.0$ V ± 0.5 V. Transmission driving tests are performed at $V_{CC} = 5.5$ V with a 2 ms duration max.
- 2/ The V_{IH} and V_{IL} tests are not required and shall be applied as forcing functions for the V_{OH} and V_{OL} tests.
- 3/ Power dissipation capacitance (C_{pp}), determines the dynamic power consumption, $P_D = (C_{PD} + C_L) V_{CC}^2 f + I_{CC} V_{CC}$, and the dynamic current consumption (I_S) is, $I_S = (C_{PD} + C_L) V_{CC} f + I_{CC}$.
- 4/ AC limits at $V_{CC} = 5.5$ V are equal to limits at $V_{CC} = 4.5$ V and guaranteed by testing at $V_{CC} = 4.5$ V. Minimum ac guaranteed for $V_{CC} = 5.5$ V by guardbanding $V_{CC} = 4.5$ V limits to 1.5 ns (minimum). AC testing at $V_{CC} = 3.0$ V shall be guaranteed, if not tested, to the specified limits.

3.2.4 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.

3.3 Electrical performance characteristics. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and apply over the full case operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

3.5 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in MIL-BUL-103 (see 6.6 herein).

3.6 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-BUL-103 (see 6.6 herein). The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

3.7 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).

3.9 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).

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Device types	01		02	
Case outline	C, D	2	R, S	2
Terminal number	Terminal symbol			
1	1A	NC	1Y	VCC
2	1Y	1A	2Y	NC
3	2A	1Y	3Y	3A
4	2Y	2A	GND	2A
5	3A	NC	GND	1A
6	3Y	2Y	GND	1Y
7	GND	NC	GND	2Y
8	4Y	3A	4Y	3Y
9	4A	3Y	5Y	GND
10	5Y	GND	6Y	GND
11	5A	NC	6A	GND
12	6Y	4Y	5A	GND
13	6A	4A	4A	4Y
14	VCC	5Y	NC	5Y
15	---	NC	VCC	6Y
16	---	5A	VCC	6A
17	---	NC	NC	5A
18	---	6Y	3A	4A
19	---	6A	2A	NC
20	---	VCC	1A	VCC

FIGURE 1. Terminal connections.

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Device types 01 and 02

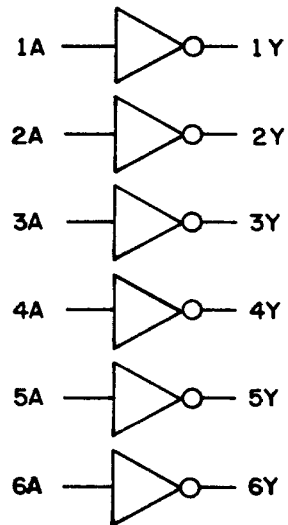


FIGURE 2. Logic diagram.

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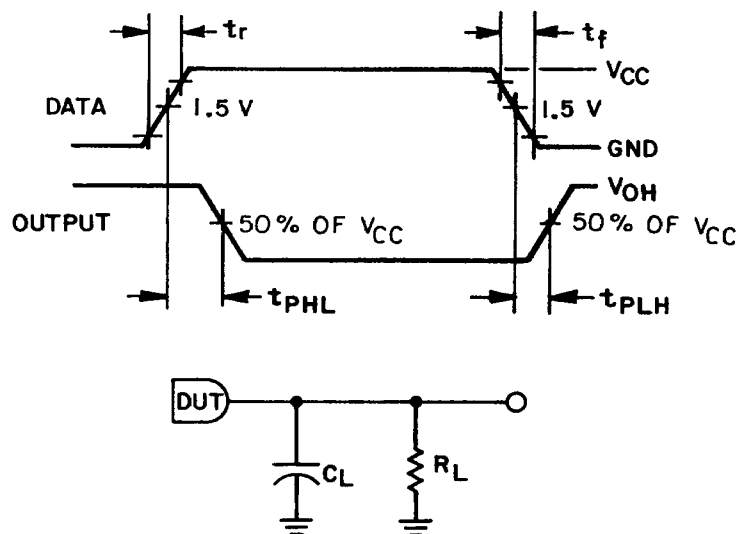
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Device types 01 and 02

Truth table each gate	
Input	Output
A	Y
H	L
L	H

H = High voltage level
L = Low voltage level

FIGURE 3. Truth table.



NOTES:

1. $t_r = t_f = 3.0 \text{ ns}$, 10 percent to 90 percent or equivalent.
2. $R_L = 500 \Omega$, $C_L = 50 \text{ pF}$ or equivalent.

FIGURE 4. Switching waveforms and test circuit.

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4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

a. Burn-in test, method 1015 of MIL-STD-883.

(1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.6 herein).

(2) $T_A = +125^{\circ}\text{C}$, minimum.

b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

a. Tests shall be as specified in table II herein.

b. Subgroups 5 and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.

c. Subgroup 4 (C_{IN} and C_{PD} measurements) shall be measured only for the initial test and after process or design changes which may affect capacitance. Test all applicable pins on 5 devices with zero failures.

d. Subgroups 7 and 8 tests shall verify the truth table as specified on figure 3.

4.3.2 Groups C and D inspections.

a. End-point electrical parameters shall be as specified in table II herein.

b. Steady-state life test conditions, method 1005 of MIL-STD-883.

(1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.6 herein).

(2) $T_A = +125^{\circ}\text{C}$, minimum.

(3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

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TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table 1)
Interim electrical parameters (method 5004)	---
Final electrical test parameters (method 5004)	1*,2,3,7,8,9
Group A test requirements (method 5005)	1,2,3,4,7,8,9, 10,11
Groups C and D end-point electrical parameters (method 5005)	1,2,3

* PDA applies to subgroup 1.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

6.2 Replaceability. Replaceability is determined as follows:

- a. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- b. When a QPL source is established, the part numbered device specified in this drawing will be replaced by the microcircuit identified as part number M38510/75701B--.

6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-481 using DD Form 1693, Engineering Change Proposal (Short Form).

6.4 Record of users. Military and industrial users shall inform Defense Electronics Supply Center when a system application requires configuration control and the applicable SMD. DESC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DESC-ECS, telephone (513) 296-6022.

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6.5 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

6.6 Approved sources of supply. Approved sources of supply are listed in MIL-BUL-103. Additional sources will be added to MIL-BUL-103 as they become available. The vendors listed in MIL-BUL-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DESC-ECS. The approved sources of supply listed below are for information purposes only and are current only to the date of the last action of this document.

Military drawing part number	Vendor CAGE number	Vendor similar part number 1/	Replacement military specification part number
5962-8760901CX	27014 18714	54AC04DMQB CD54AC04F/3A	M38510/75701BCX
5962-8760901DX	27014	54AC04FMQB	M38510/75701BDX
5962-87609012X	27014	54AC04LMQB	M38510/75701B2X
5962-8760902RX	01295	SNJ54AC11004J	
5962-8760902SX	01295	SNJ54AC11004W	
5962-87609022X	01295	SNJ54AC11004FK	

1/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number

Vendor name and address

01295

Texas Instruments Incorporated
P.O. Box 60448
Midland, TX 79711-0448

18714

RCA Corporation
Semiconductor Sector
Route 202
Somerville, NJ 08876

27014

National Semiconductor
333 Western Avenue
South Portland, ME 04106

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